## **ELECTRONIC INFORMATION DISCLOSURE STATEMENT**

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Title of Invention

CIRCUIT AND METHOD FOR MONITORING DEFECTS

Application Number: Confirmation Number:

First Named Applicant: Greg Bazan

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Search string:

(6556949 or 6513151 or 6473665 or 6470485 or 6470229 or 6389323 or 6341241 or 6210983 or 6185707 or 6017771 or 5999003 or 5675589 or 5550843 or T994007

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## **US Patent Documents**

## Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	6556949	2003-04-29	Lyon			
	2	6513151	2003-01-28	Erhardt et al.			
	3	6473665	2002-10-29	Mugibayashi et al.			
	4	6470485	2002-10-22	Cote et al.			
	5	6470229	2002-10-22	Wang et al.			
	6	6389323	2002-05-14	Yang et al.			
	7	6341241	2002-01-22	Mugibayashi et al.			
	8	6210983	2001-04-03	Atchison et al.			
	9	6185707	2001-02-06	Smith et al.			
	10	6017771	2000-01-25	Yang et al.			
	11	5999003	1999-12-07	Steffan et al.			
	12	5675589	1997-06-07	Yee			
	13	5550843	1996-08-27	Yee			
	14	T994007	1976-03-02	Booth, Jr. et al.			

## Signature

Examiner Name	Date